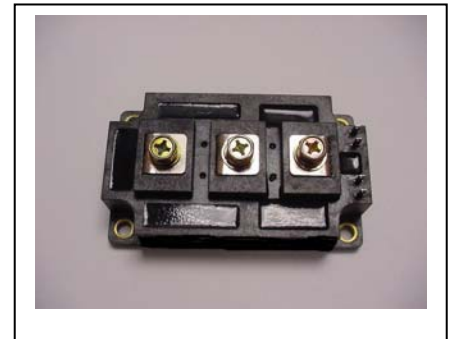
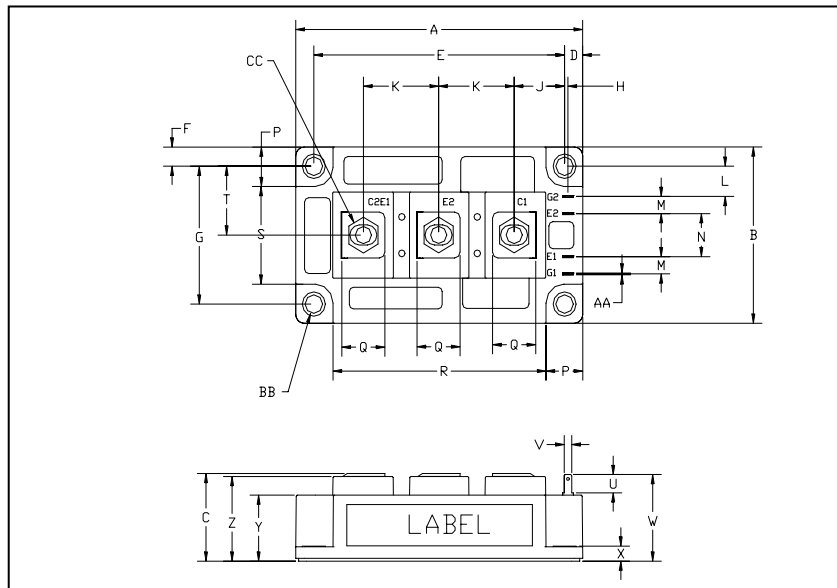


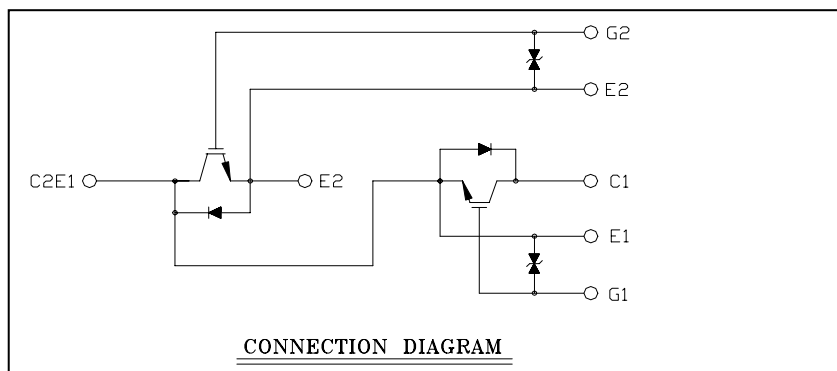


Description:

Powerex Dual IGBT Module is designed specially for customer applications.

Features:

- Low Drive Requirement
- Low $V_{CE(sat)}$
- Super Fast Diode
- (4) H Series 150A 600V Chips per IGBT Switch
- (6) H Series 100A 600V Chips per Diode
- Copper Base Plate
- Low Thermal Resistance
- Aluminum Nitride DBC Ceramic



Dim	Inches	Millimeters
A	4.19	106.4
B	2.42	61.4
C	1.30	33.0
D	0.26	6.6
E	3.66	93.0
F	0.26	6.7
G	1.89	48.0
H	0.05	1.20
J	0.74	18.7
K	1.10	27.9
L	0.41	10.5
M	0.24	6.0
N	0.59	15.0
P	0.54	13.6

Dim	Inches	Millimeters
Q	0.63	16.0
R	3.11	79.0
S	1.34	34.0
T	0.94	24.0
U	0.25	6.4
V	0.11	2.8
W	1.29	32.7
X	0.31	7.8
Y	1.00	25.5
Z	1.26	32.0
AA	0.20	0.5
BB	0.256 Dia.	6.5 Dia.
CC	6 Hex Nut	6 Hex Nut

Maximum Ratings, T_j=25°C unless otherwise specified

Ratings	Symbol	QID0660009	Units
Collector Emitter Voltage	V _{CES}	600	Volts
Gate Emitter Voltage	V _{GES}	±20	Volts
Collector Current	I _C	600	Amperes
Peak Collector Current	I _{CM}	1200*	Amperes
Diode Forward Current	I _F	600	Amperes
Diode Forward Surge Current	I _{FM}	1200*	Amperes
Power Dissipation	P _d	1670	Watts
Junction Temperature	T _j	-55 to 150	°C
Storage Temperature	T _{stg}	-55 to 125	°C
Mounting Torque, M6 Terminal Screws	-	26	In-lb
Mounting Torque, M6 Mounting Screws	-	26	In-lb
Module Weight (Typical)	-	460	Grams
V Isolation	V _{RMS}	1800	Volts

*Pulse width and repetition rate should be such that device junction temperature does not exceed device rating.

Static Electrical Characteristics, T_j=25°C unless otherwise specified

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Collector Cutoff Current	I _{CES}	V _{CE} =V _{CES} V _{GE} =0V	-	-	1.0	mA
Gate Leakage Current	I _{GES}	V _{GE} =V _{GES} V _{CE} =0V	-	-	0.5	μA
Gate-Emitter Threshold Voltage	V _{GE(th)}	I _C =60mA, V _{CE} =10V	4.5	6.0	7.5	Volts
Collector-Emitter Saturation Voltage	V _{CE(sat)}	I _C =600A, V _{GE} =15V	-	2.1	2.8*	Volts
		I _C =600A, V _{GE} =15V, T _j =150°C	-	2.15	-	Volts
Total Gate Charge	Q _G	V _{CC} =600V, I _C =600A, V _{GS} =15V	-	1800	-	nC
Diode Forward Voltage	V _{FM}	I _E =600A, V _{GS} =0V	-	-	2.8	Volts

*Pulse width and repetition rate should be such that device junction temperature rise is negligible.

Dynamic Electrical Characteristics, T_j=25°C unless otherwise specified

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Input Capacitance	C _{ies}	V _{GE} =0V	-	-	60	nF
Output Capacitance	C _{oes}	V _{CE} =10V	-	-	21	nF
Reverse Transfer Capacitance	C _{res}	f=1MHz	-	-	12	ns
Turn on Delay time	t _{d(on)}	V _{CC} =300V	-	-	350	ns
Rise Time	t _r	I _C =600A	-	-	700	ns
Turn- off Delay Time	t _{d(off)}	V _{GE1} =V _{GE2} =15V	-	-	350	ns
Fall Time	t _f	R _G =1.0Ω	-	-	300	ns
Diode Reverse Recovery Time	t _{rr}	I _F =600A	-	-	110	ns
Diode Reverse Recovery Charge	Q _{rr}	di _F /dt=-1200A/μS	-	1.62	-	μC

Thermal and Mechanical Characteristics, T_j=25°C unless otherwise specified

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal Resistance, Junction to Case	R _{θJC}	Per IGBT	-	-	0.06	°C/W
Thermal Resistance, Junction to Case	R _{θJC}	Per Diode	-	-	0.12	°C/W
Contact Thermal Resistance (Thermal Grease Applied)	R _{θCF}	Per Module	-	-	0.04	°C/W